CT2300

Datasheet

Digital Multimeter Accessory Kit

Full offering DMM accessory kit for Electrical or Electronic Applications...

Description

Full offering of accessories for Electrical or Electronic Applications. Both large and micro-sized probe bodies, flexible pincer clip for long reach applications, fully insulated alligator clips for over-sized lugs or fine wires, and spade lug or banana plug adapters for fixed terminal connections. All this utility while meeting the latest international safety standards.

- IEC 61010-031 rated accessories
- PVC jacketed lead wire
- Replaceable Tip Probe 4mm cage spring and 2mm smooth tip
- Cap on 4mm cage spring tip provides CAT III on probe bodies
- 0.7mm SS Spring Tip probe for fine work
- Extra large alligator clips for electrical work

Kit Contains:

- (2) Modular probes, (1) Black (1) Red
- (2) Flex Pincer Clips, (1) Black (1) Red
- (2) Extra-Large Insulated Alligator Clip, (1) Black (1) Red
- (2) 4mm Banana Plug to Banana Jack Adapter, (1) Black (1) Red
- (2) Spring Tip Mini-Probe, (1) Black (1) Red
- (2) 6mm Spade Lug Adapter, (1) Black (1) Red
- (2) Banana Test Leads, 4mm Sheath Plug to Right-Angle Sheath Plug, PVC Jacket, 100 cm (40"), (1) Black (1) Red



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All specifications apply to the unit after a temperature stabilization time of 20 minutes over an ambient temperature range of 25° C \pm 5° C.

Specifications

Probe Bodies	1,000 V CAT III w/c	ap (CAT II w/o), 36 A
Flex Pincers Clips	1,000 V CAT II	
ExLg Alligator Clips	1,000 V CAT III / 60	0 V CAT IV, 36 A
Plug Adapter	33 Vac / 70 Vdc, 10	A
Spring Tip Probe Bo	860109sV CAT II, 1 A	
Spade Lug	33 Vac / 70 Vdc, 10	A
Test Leads	1,000 V CAT III / 60	0 V CAT IV, 20 A
Temperature (degrees)		-20 Cto +80 C
RoHS (2011/65/EU)		Compliant

Specifications are subject to change without notice. To ensure the most current version of this manual, please download the current version from our website: caltestelectronics.com



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